





Phase Noise and Jitter in Digital Electronics

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Outline

- Basics
- FPGAs Mechanisms / Examples / Facts
- ADCs Basics / Examples
- DDSs Basics / Advanced / Examples
- \cdot Dividers Π and Λ / Microwave

home page http://rubiola.org

Acknowledgments

This tutorials gathers a wealth of (mostly unpublished) material developed by

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chiefly Pierre-Yves "PYB" Bourgeois Gwenhael "Gwen" Goavec-Merou Jean-Michel Friedt Yannick Gruson

Claudio Calosso, INRIM, Torino, Italy

...and myself

Caveat

Only a fraction of this can be taught at a 1–2 H session



Jitter

$v(t) = V_0 \left[1 + \alpha(t)\right] \cos\left[2\pi\nu_0 t + \varphi(t)\right]$

- $\mathbf{x}(t) = \frac{\varphi(t)}{2\pi\nu_0}$
- ITU defines jitter as the variations in the significant instants of a clock or data signal, vs a "perfect" clock
- Jitter —> Usually fast phase changes f > a few tens of Hz
- Wander —> Usually slower phase changes (due to temperature, voltage, etc)
- Designers first care about consistency of logic functions,
 - First, maximum timing error
 - Sometimes RMS value and probability distribution
- Time and Frequency community focuses on
 - PM noise spectra
 - Delay spectra
 - Two-sample variances (ADEV, TDEV, etc.)

Phase Time x(t) — or Jitter

- Let's allow $\varphi(t)$ to exceed $\pm \pi$, and count the no of turns
- This is easily seen by scaling ω down (up) to $\omega = 1$ rad/s using a noise-free gear work
- The phase-time fluctuation associated to $\varphi(t)$ is

 $\mathbf{x}(\mathbf{t}) = \boldsymbol{\varphi}(\mathbf{t}) / \boldsymbol{\omega}_0$



Physical Concept of PSD S(f)

Power Spectral Density



- The PSD is the distribution of power vs. frequency (power in 1-Hz bandwidth)
- The PS is the distribution of energy vs. frequency (energy in 1-Hz bandwidth)
- Frequency can be continuous or discrete (histogram),
- In mathematics,
 - the power is a square quantity
 - the energy is power integrated in time
- Power (energy) in physics is a square (integrated) quantity
 - PSD -> W/Hz (or V²/Hz, A²/ Hz, etc.)

The Polynomial Law $v(t) = V_0 [1 + \alpha(t)] \cos [2\pi\nu_0 t + \varphi(t)]$



Phase Noise PSD
$$_0$$

 $S_{arphi}(f) = \sum_{i \leq -4} \mathsf{b}_i f^i$

Jitter (phase-time) PSD $x(t) = \frac{\varphi(t)}{2\pi\nu_0}_0$ $S_x(f) = \sum_{i \le -4} k_i f^i$

Fractional Frequency PSD

$$\mathbf{y}(t) = \dot{\mathbf{x}}(t) = \frac{\dot{\varphi}(t)}{2\pi\nu_0}$$
$$S_{\mathbf{y}}(f) = \sum_{i < -2}^{2} \mathbf{h}_i f^i$$

Converting PM noise to TDEV

b₀

 b_0

 $\overline{2(2\pi\nu_0)^2\tau}$

Τ

 $rac{2\ln(2) \mathsf{b}_{-1}}{(2\pi
u_0)^2}$

Sa

 $\sigma_{\chi}(\tau)$

random phase

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phase-time (fluctuation)



TDEV σ_x(τ) same as ADEV, but we use x(t) instead of y(t)

You may be more familiar to $\sigma_y^2(\tau) = h_0/2\tau + 2\ln(2)h_{-1}$

Phase Noise Sampling



Sampling occurs at the edges

- (in some cases, only at rising or falling edges)
- Square wave signals need analog bandwidth at least
 - 3 v_{max} ... 4 v_{max}
- Aliasing is expected

Aliasing Over-Simplified



- The Parseval Theorem states that the total energy (or power) calculated in the time domain and in the frequency domain is the same
- Ergodicity allows to interchange time domain and statistical ensemble

N'B' = *N"B"*



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...and PM noise scales up with the reciprocal of the carrier frequency

Aliasing and 1/f Noise



And virtually no effect with $1/f^2$, $1/f^3$, $1/f^4$...



- Noise Mechanisms
- Examples
- Additional Facts

Noise Mechanisms

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FPGA Interconnection Structure¹⁴



Device dependent blocks

- Input/Output
- RAM
- PLL
- NCO
- ...etc.

Delay & jitter

- General routing through switch points
 - Delay & jitter rather uniform in a block
 - Large spread over the interconnect matrix
- Dedicated clock lines managed separately
 - Low and predictable delay & jitter

Output Jitter Limitations

- Output can be synchronized to the clock
- Jitter cannot be smaller than
 - External clock signal
 - Clock input stage
 - Clock distribution
- Output stage internal data ck in ck in



out

Phase Noise in the Input Stage



Phase Noise in the Input Stage¹⁷

Sinusoidal signal

 $v(t) = V_0 [1 + \alpha(t)] \cos [2\pi\nu_0 t + \varphi(t)] \implies SR = 2\pi\nu_0 V_0$



φ-type noise

 $S_{\varphi}(f) = \frac{S_n(f)}{V_0^2}$

constant vs ν_0

φ-type PM Noise

Remember that white noise is subject to aliasing, flicker is not



Power law $S_n(f) = \sum h_i f^i$ [do not mistake with $S_y(f)$]

φ-type Jitter



Power law $S_x(f) = \sum k_i f^i$ and $S_n(f) = \sum h_i f^i$

Internal Delay Fluctuation

x-type noise



- The internal delay fluctuates by an amount x(t)
- This has nothing to do with threshold and frequency

x-type Jitter

Remember that white noise is subject to aliasing, flicker is not



Power law $S_x(f) = \sum k_i f^i$

x-Type PM Noise

Remember that white noise is subject to aliasing, flicker is not



Full Noise Mechanism



- The φ-type noise noise may show up or not, depending on input noise and SR
- At the comparator out, the edges attain full SR and bandwidth of the technology
- Complex distribution -> independent fluctuations add up $x(t) = \sum_{i} x_i(t)$ and $\langle x^2(t) \rangle = \sum_{i} \langle x_i^2(t) \rangle$



Summary of the Noise Types

Noise class	Dependence on ν_0	
	$S_{\varphi}(f)$	$S_{x}(f)$
Pure φ -type	C vs. ν_0	$1/\nu_{0}^{2}$
Aliased φ -type	$1/ u_{0}$	$1/ u_{0}^{3}$
Pure x-type	$ u_0^2 $	C vs. ν_0
Aliased x-type	$ u_0 $	$1/ u_{0}$

- Pure x-type. High speed circuits, inside the device. Must be 1/f, otherwise aliasing shows up
- Aliased x-type. High speed circuits, inside the device, at low switching frequency. The clock must be either high frequency sin(), or sharp square wave, so that the threshold has no effect.

Noise Types and AVAR



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Examples

Measurements are performed with the Symmetricom (Microsemi) DS 5125 and DS 5120 dual-channel phase meter



Allow (input frequency) ≠ (ref frequency)

Cyclone III Clock Buffer



Flicker

- High v₀ -> scales as v₀ (x-type)
- Low v₀, -> to φ-type (bumps 0.1–10 Hz)

White

• Aliasing shows up at low v₀

Cyclone III Output Buffer



MAX 3000 CPLD [300 nm] (1)



Flicker region –> Negligible aliasing

- The Π divider is still not well explained
- The Λ divider exhibits low 1/f and low white noise

MAX 3000 CPLD [300 nm] (2)



- Slope $1/\tau$, typical of white and flicker PM noise
- The Λ divider performs 2×10⁻¹⁴ at τ = 1 s, 10 MHz output

Max V CPLD [180 nm]

We do not trust this spectrum (bump -> supply voltage?)



- Two lambda dividers
 - output-to-output and common clock,
 - low f, emphasizes the 1/f noise
- Same, only output-tooutput and common clock



Max V CPLD [180 nm]

We do not trust this spectrum (bump -> supply voltage?)



- Two lambda dividers
 - output-to-output and common clock,
 - low f, emphasizes the 1/f noise
- Clock, difference between the two outputs

Cyclone II A Divider [90 nm]



Cyclone II Clock Buffer [90 nm]³⁵



Zynq (28 nm), Λ Divider


74S140 – Old TTL 50 Ω Driver



Some Facts Related to Phase and Noise

- Volume Law
- Input Chatter
- Internal PLL
- Thermal Effects

Rationale for the Volume Law





- Flicker coeff b₋₁ is ≈ independent of power
- The flicker of a branch is not increased by splitting the input power
- The carrier adds up coherently, the phase noise adds up statistically
- Hence, the 1/f phase noise is reduced by a factor m

Gedankenexperiment

- Flicker is of microscopic origin (Gaussian -> central limit theorem)
- Join the m branches of a parallel device forming a compound
- 1/f PM is proportional to the inverse size of the active region

The Volume Law!



Details in file DevicesComparison.doc

Input Chatter (1/3)



Chatter occurs when the RMS Slew Rate of noise exceeds the slew rate of the pure signal

Pure signal

$$v(t) = V_0 \cos(2\pi\nu_0 t)$$

$$SR = 2\pi\nu_0 V_0$$

Wide band noise

$$\left< \text{SR}^2 \right> = 4\pi^2 \int_0^B f^2 S_V(f) \, df$$
$$= \frac{4\pi^2}{3} \sigma_V^2 B^2 \quad \text{(rms)}$$

Chatter threshold

$$\nu_0^2 = \frac{1}{3} \, \frac{S_v B^3}{V_0^2}$$

With high-speed devices, chatter can occur at unexpectedly high frequencies

Example

- V₀ = 100 mV peak
- 10 nV/√Hz noise
- 650 MHz max -> 2 GHz noise BW
- Chatter threshold v = 5.2 MHz

Simulation of Chatter (2/3)



 $v_0 = 1 Hz$, $V_0 = 1 V_{peak}$ $\sqrt{\langle v_0^2 \rangle} = 10 \text{ mV}$ rms noise Noise BW

increases in powers of 2

De-normalize for your needs

Input Chatter – Example (3/3)

Good agreement with theory





Experiment

- Cyclone III FPGA
- Estimated noise 10 nV/√Hz

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- Estimated BW 2 GHz
- $V_0 = 50 \text{ mV} (100 \text{ mV}_{pp})$ $v_0 = 4.7 \text{ MHz}$
- $V_0 = 100 \text{ mV} (200 \text{ mV}_{pp})$ $v_0 = 4.7 \text{ MHz}$

Asymmetry shows up Explanation takes a detailed electrical model, which we have not

Cyclone III Internal PLL (1/4)

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A Λ divider (inside the FPGA) enables the measurement

- The divider noise is low enough
- A trick to work at low frequency

Cyclone III Internal PLL (2/4)⁴⁵



- Low-Q LC oscillator (Q \approx 10), 0.6–1.3 GHz
- Optional ÷2 always present
- We set D = 1 (for lowest noise)
- QUARTUS decides C and N

Cyclone III Internal PLL (3/4) PLL used as a buffer



Crossover between phi-type and x-type at 20 MHz



x-type -> analog noise in the phase detector

Cyclone III Internal PLL (4/4) PLL used as a frequency multiplier



Stability 1.5x10⁻¹² @ 1 s $(f_{\rm H} = 500 \text{ Hz})$

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-115 dB + 20 log₁₀(v₀) in MHz



1/f phase noise is dominant

• Scales as $N^2 \rightarrow analog$ noise in the phase detector

Thermal Effects (1/3)

Principle

- FPGA dissipation change ΔP by acting on frequency
- Energy $E = CV^2$ dissipated by the gate capacitor in a cycle

Conditions

- Cyclone III used as a clock buffer
- Environment temperature fluctuations are filtered out with a small blanket (necessary)
- Two separate measurements (phase meter and counter) -> trusted result

Outcome

- (1) Thermal transient, due to the change of the FPGA dissipation
- (2) Slow thermal drift, due to the environment
- (3) Overall effect of ΔP



Thermal Effects (2/3)



Warning: In real applications, other parts of the same FPGA impact on the temperature, thus on phase – drift is possible

Thermal Effects (3/3)



Cyclone III, Voltage Supply



- All but one low-noise voltage supplies
- The noise is critical only in the core supply

Threshold-Noise Measurement⁵²

Vdd

Gnd

out





- Measure the voltage (current) fluctuation needed to stabilise at the threshold
- Works only on simple (old) circuits
- Threshold-mismatched cascade -> gain not accessible
- FPGAs complexity make the analog gain inaccessible





Transfer Function & Quantization



Kester W (ed), Analog-Digital Conversion, Fig.2.15, p.2.14, Analog Devices 2004, ISBN 0-916550-27-3

Spectrum of the Quantization Noise





Ergodicity suggests that the quantization noise can be calculated statistically

$$\sigma^2 = \frac{V_q}{12}$$





Quantization & Sinusoidal Signals

sampting frequency fs Signal power $P_0 = \frac{V_{PP}^2}{8} = \frac{A^2 V_{FSR}^2}{8}$ VFSR VFF=AVFSR A<1 Noise power $SNR = (3/2) 2^{2m}$ $O^2 = \frac{V_{LSB}}{12}$ 6.02 m + 1.76 dB Parseval theorem $S_v = \frac{\sigma^2}{B} \Rightarrow S_v = \frac{V_{LSB}^2}{6fs}$ Warning: We assume that the noise power is equally dietributed in O-B. A This is not true Sr 02/B in our case because sampling and carrier are highly coherent. See Widraw. Koller Phase noise Sup = bo (white) $b_{0} = \frac{S_{V}}{P_{0}} \quad b_{0} = \frac{V_{LSB}}{V_{FSR}^{2}} \cdot \frac{4}{3A^{2}f_{s}}$ $b_a = \frac{1}{(2^m)^2} \frac{4}{3A^2 f_s} = \frac{6.02 \text{ m} + 1.25}{-10 \log_{10} f_s \text{ dB}}$ Apendix 9 for details. Anyway, we tempozarily accept the uniform dictribution, hoping that the reality to not too par-Aproximation (fairly large Vp) A2=213 (-1.8 db) > box (2mj2 fs

Phase Noise



6 = (2My2 3A2fs $\approx \frac{1}{(2^m)^2} \frac{2}{\beta_s}$ ь, Cost of 6 dB improvenue fs · factor-of-4 Obvious conclusion; practical ADCs feature

lower bo at low for becreun

of the higher no of bits





- Analog noise is higher than quantization noise
- Given a voltage V -> random distribution of output N
- This correct $\rightarrow V^2 = V^2_{analog} + V^2_{quant}$ (don't spoil the resolution with insufficient no of bits)

Information (bits)

$$I = \sum_{i} -p_i \log_2(p_i)$$

Equivalent No of Bits

$$ENoB = log_2$$



Digital Filter and Decimation



- Convolution with low-pass h(t)
- 127 coeff. Blackman-Harris kernel provides 70 dB stop-band attenuation
- Future: we will use >>127 coefficients



Digital Down Conversion



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Examples

Hardware

ADC type	AD9467 / Single Alazartech	LTC2145 / Dual Red Pitaya	LTC2158 / Dual Eval board
Platform	Computer	Zynq (onboard)	Zynq (separated)
Sampling <i>f</i> Input BW	250 MHz 900 MHz	125 MHz 750 MHz	310 MHz 1250 MHz
Bits / ENoB	16 / 12	14 / 12	14 / 12
Exp.noise (2V _{fsr})	-158 dBV ² /Hz	-155 dBV ² /Hz	-159 dBV ² /Hz
Delay / Jitter	1.2 ns / 60 fs	0? / 100 fs diff 0? / 80 fs single	1 ns / 150 fs
Power supply	1.8 V & 3.3 V 1.33 W	1.8 V 190 mW	1.8 V 725 mW

Dissipation is relevant to thermal stability

For reference, 100 fs jitter is equivalent to				
carrier f	φrms	$S\varphi(f) = b_0$	10 log ₁₀ [L(f)]	
10 MHz	6.3 µrad	4x10 ⁻¹⁸ rad ² /Hz	–177 dBc/Hz	
100 MHz	63 µrad	4x10 ⁻¹⁷ rad ² /Hz	–167 dBc/Hz	

Sampling Frequency



Transition Noise Measurement ⁶⁶



The differential clock jitter introduces additional noise due to the asymmetry between AM and PM

At 10 MHz input, \approx 100 fs the effect of jitter does not show up

LT 2158 Noise



10 MHz, $V_{pp} \approx 0.95 V_{FSR}$

LT2145 (Red Pitaya) Noise



10 MHz, $V_{pp} \approx 0.95 V_{FSR}$

AD9467 (Alazartech) Noise



10 MHz, V_{pp} ≈ **0.95 V**_{FSR}

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70 Application to 10 GHz Cryogenic Oscillators



- Rejects the common-path jitter
- Takes in the differential jitter

Results



- Background noise 5–6 dB higher than that of the TSC5125
- We use 2 channel cross spectrum
- TSC5125 uses 4 channel cross spectrum

The Four-Channel Scheme


Background Noise



Compared to a Commercial Instrument

- this is done only to make sure that there is no calibration mistake -



Conclusions

White noise

- Depends on Fs and ENoB
- Fits well the expectation
- Flicker –110 dBV²/Hz best found
- First phase noise measurements, (direct & beat)
- Background –185 dBc with 4-channel scheme
- Modeling common-mode and differential jitter in progress
- Unwanted correlated effects still unknown

4 – DDSs

- Basics
- Advanced
- Experiments



Basic DDS scheme



 $\Im\{z\}$

time $t = k/\nu_c$

AD9912, a popular fast DDS

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48 bit accumulator, 14 bit DAC, 1 GHz clock



AD9854, a popular DDS

48 bit accumulator, 300 MHz clock, 12 bit DAC, I-Q output, AM/PM/FM capability



The noise-free synthesizer



- The noise-free synthesizer propagates the jitter x (phase time)
 - So, it scales the phase ϕ as N/D,
 - and the phase spectrum \pmb{S}_{ϕ} as $(\pmb{N}/\pmb{D})^2$
- Notice the absence of sampling

The Egan model

for phase noise in frequency dividers



For N/D <<1, the scaled-down noise hits the output-stage limit

W.F. Egan, Modeling phase noise in frequency dividers, TUFFC 37(4), July 1990

Quantization noise

W. R. Bennett, Spectra of quantized signals, Bell System Tech J. 27(4), July 1948





Background noise



Sigual power $P_0 = \frac{V_{PP}^2}{8} = \frac{A^2 V_{FSR}}{8}$ Noise power $O^2 = \frac{V_{LSB}^2}{12}$ Parseval theorem $S_v = \frac{\sigma^2}{B} = \frac{1}{2} f_s = \frac{V_{LSR}}{6} f_s$ Phase noise Scp = bo (white) $b_{0} = \frac{S_{V}}{P_{0}} \quad b_{0} = \frac{V_{LSB}}{V_{FSR}^{2}} \cdot \frac{4}{3A^{2}f_{s}}$ ba = 1/2 3A2 fs Aproxima teon (fairly large Up) A2 = 213 (-1.8 db) > box (2mj2 fs

Background noise



1 (2M)2 x b,

Cost of 6 dBimpsovement . 16ct . jactor-of-4 fs

Obvious conclusion: practical ADCs feature lower boat low for beceun of the higher no. of bits

Advanced

State-variable truncation

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Spurs -> next

Truncation generates spurs



The power of spurs comes at expenses of white noise – yet not as one-to-one

Nonlinearity generates spurs



PLL clock multiplier



3.3 V: lower PM noise than 1.8 V

Probably related to the cell size and to the dynamic range





AD9956 0 48 bit accu. 14 bit dac single output -10 f_=400MHz, 1.8V cmos -20 -30 -40 -50 -60 $b_{-1} = -101 \text{ dB}$ -(f) (dBc/Hz) -70 $b_0 = -152 \text{ dB}$ -80 $b_{-1} = -113 \text{ dB}$ -90 $b_0 = -159 \text{ dB}$ -100 -110 -120--130--140 -150 -160 -170 100 1k 10k 100k 10

FREQUENCY (Hz)





AD9951, AD9952, AD9953, AD9954



E. Rubiola, Mar 2007 (adapted from the Analog Devices data sheets)

Plots originally used to extract the noise parameters

High-Frequency DDSs

AD9914 12 bit, 3.5 GHz 64 bit accumulator (190 pHz res)

AD9915 12 bit, 2.5 GHz 64 bit accumulator (135 pHz res)



Residual noise is close to that of the gear-box model Plots are from the manufacturer data sheet Whether spurs are removed or not, is not said

Experiments

- AD9912 demo board
- AD9854 (9914) demo board
- Claudio's AD9854 board
 - V1 Current feedback OPA output stage
 - 25Ω input impedance, 8 nV/√Hz noise, kHz coupled
 - V2 Balun and MAV-11 RF output amplifier
 - F = 3.6 dB, AC coupled (≥1–2) MHz
 - Specified above 50 MHz, yet works well below

Experimental method (PM noise)

- Pseudorandom noise, slow beat (days)
- The probability that two accumulators are in phase is ≈ 0
- Two separate DDS driven by the same clock have a random and constant delay
- The delay de-correlates the two realizations, which makes
 the phase measurement possible

Single channel

Dual channel

kind of virtual mixer, after (sub)sampling & direct ADC





Claudio's prototypes







PM noise vs. output frequency



AD9912 noise vs. out frequency – low Fourier frequencies –



PM noise vs. output frequency



- The –140 dB floor is due to AD8002 at the DDS output
- The flicker is unchanged (comes from the DDS)

AD9854 noise AD9852, AD9854 -100two outputs: 48 bit accu, 12 bit dac cos+aux / I-Q f_=300MHz, 3.3V cmos -110 Specs, -120 PHASE NOISE (dBc/Hz) regular output -130 A_{OUT} = 80MHz $b_0 = -159 \text{ dB}$ -140 -149 dB -150 -160A_{OUT} = 5MHz -170 10 100 1k 10k 100k 1M **FREQUENCY (Hz)**

Flicker is in fair agreement White is made low by spurs

Basic formula for white noise rad^2/Hz $b_0 =$ $\overline{3}$ $\overline{2^{2n} \nu_s}$ meas, dB clock, MHz who math, dB 300 -159 -155.8specs YG -158 -155.0 250 -162.5 CC -153.6180





AD9854 I-Q noise

AD9854 ck 180 MHz I-Q PM noise. Take away 3 dB 1.40625 MHz -60for 2 equal outputs (DACs) 2.8125 MHz Flicker is in quite a good 5.625 MHz Phase Noise Power Spectrum $dB_{ m rad^2/Hi}$ agreement between YG and CC 11.25 MHz $b_{1} = -118 \text{ dB},$ -8022.5 MHz scales as 1/v² 45 MHz I-Q spectra cannot be -100compared to specs -140 dB@ 180 MHz: (opa AD8002 white) -30 -120 'dds3_clock_250MHz_out_IQ 'dds3_clock250MHz_out_IQ_I 'dds3_clock_250MHz_out_IQ_20M 'dds3_clock250MHz_out_IQ_4 'dds3_clock250MHz_out_IQ_8 -40-50 -140-60 -70hits b_1 = -132 dB 250 MHz clock, I–Q noise -160-80INRIM -90 10⁻¹ 10⁰ 10^{1} 10^{-4} 10⁻³ 10⁻² 10^{2} 10^{4} 10⁵ 10^{6} 10^{3} -100Fourier Frequency (Hz)-110-120hits -158 dB -130-140-150-160-170-18010 100 1000 10000 100000 f (Hz)

PM noise vs. output amplitude



- PM noise scales 6 dB per factor-of-two output amplitude
- Signature of digital multiplication: lower amplitude is obtained by reducing the integer number at the DAC input

High-frequency DDSs

AD9915 12 bit, 2.5 GHz 64 bit accumulator (135 pHz res)



PM noise vs. clock amplitude



The effect of the clock frequency



Thermal effects



- f (Hz)
 Low-frequency temperature fluctuations induce phase noise
- A large thermal mass helps



AD9912 Voltage sensitivity



AD9912 temperature sensitivity¹⁰⁸



• Temperature control (chamber)

Measured: -2 ps/K

 Includes cables, baluns etc


AD9912 sensitivity to temperature (alternate)

AD9912 temperature sensitivity¹¹⁰



High frequency: –2 ps/K, constant

Low frequency: 1/v³ law

PM noise of the AD 9912



- At 50 MHz and 10/12.5 MHz we get ≈15 dB lower flicker than the data-sheet spectrum
- Experimental conditions unclear in the data sheets

Spurs reduce the white noise



Spurs can be amazing



More about a PM-noise bump

- Low PSRR (power-supply rejection ratio) of PM noise
- For instance The AD9912 at 25 MHz out has 15 ps/% supply-voltage sensitivity
- No bump at 10³–10⁵ Hz is seen in the data-sheet spectra
- DC regulator may show a similar bump, alone or or with the output capacitor



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X7R SMD capacitor shows low ESR ($\leq 5 \text{ m}\Omega$)

PLL clock multiplier





PLL clock multiplier

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AD9912: 10->640->10, carrier at 1.3 MHz



PLL clock multiplier



Effect of other parts on the PCB



A blinking LED somewhere on the PCB spoils the output spectrum

ADEV vs. clock frequency



ADEV vs. output frequency



ADEV vs. output frequency



Experimental method (AM noise) Cross-spectrum



$$v_a(t) = 2k_a P_a \alpha(t) + \text{noise}$$

 $v_b(t) = 2k_a P_b \alpha(t) + \text{noise}$

The cross spectrum $S_{ba}(f)$ rejects the single-channel noise because the two channels are independent.

$$S_{ba}(f) = \frac{1}{4k_a k_b P_a P_b} S_\alpha(f)$$



E. Rubiola, The measurement of AM noise of oscillators, arXiv:physics/0512082, Dec. 2005 E. Rubiola, F. Vernotte, The cross-spectrum experimental method, arXiv:1003.0113v1 [physics.ins-det], Feb. 2010

AM noise (1)





AM noise (2)



f(Hz)

-180

Conclusions

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- Noise theory and model for the DDS
- A lot of still-not-published experimental data
 - Phase noise
 - Allan deviation
 - Amplitude noise
- Experiments done at INRIM and at FEMTO-ST
- Model and experimental data are in fair agreement

http://rubiola.org

5 – Dividers

- Π and Λ Dividers
- Microwave Dividers

Π and Λ Dividers

Motivations

Seminal article by W. F. Egan (1990)

- Milestone in the domain, never forget it
- However, TTL and ECL logic families are now obsolete
- Microwave (photonics) –> highest spectral purity
- Transfer the spectral purity to HF/VHF
 - Dividers are more comfortable than multipliers
 - NIST now uses analog dividers

Nowadays digital electronics is fantastic

- CPLD & FPGA -> Easy to duplicate
- High number of gates for cheap
- High toggling frequency (1.5 GHz)

W. F. Egan Egan WF, Modeling phase noise in frequency dividers, IEEE T UFFC 37(4), July 1990
E. Rubiola & al, Phase noise in the regenerative frequency dividers, IEEE T IM 41(3), June 1992
A. Hati & al, Ultra-low-noise regenerative frequency divider..., Proc IEEE IFCS, May 2012

The Gear Work Model

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W. F. Egan Egan WF, Modeling phase noise in frequency dividers, IEEE T UFFC 37(4), July 1990

Parseval Theorem

The energy calculated in the time domain is equal to the energy calculated in the frequency domain



For ergodic signals, the time average is equal to the ensemble average

Sampling and Aliasing

Energy conservation applies to the unfiltered signal



 Multiple aliases overlap to the main part of the spectrum 131

 With white noise, the PSD increases by B/f_N (Bandwidth / Nyquist f)

Downsampling increases the (PM) noise spectrum

High f_N Low f_N $-N = \sigma^2 / f_N$ $N = \sigma^2 / f_N$ f_N f_N

Aliasing and 1/f Noise



PM-Noise Aliasing in the Input Stage



Convert the input sinusoid into a square wave, as appropriate



- Edge-sampling at 2v_i inherent in the sin-to-square conversion
- Full-bandwidth (B) noise is taken in
- The phase-noise Nyquist frequency is vi
- The sampling process increases the noise by B/v_i

Eventually, clipping removes the AM noise [Pfaff 1974]

Aliasing in **Π** Divider

Regular synchronous divider The Greek letter Π recalls the square wave ΠΠΠΠ



output sampling frequency $\nu_o = 2\frac{1}{D}\nu_i$

- The gearbox scales Sφ down by 1/D²
- The divider takes 1 edge out of D
 - Raw decimation without low-pass filter
 - Aliasing increases Sφ by D
- Overall, Sφ scales down by 1/D



The Λ Divider – Little/no Aliasing

New divider architecture Series of Greek letters AAAAA recalls the triangular wave



- Gearbox and aliasing -> 1/D law
- Add *D* independent realizations shifted by 1/2 input clock,
- reduce the phase noise by 1/D,
- ... and get back the $1/D^2$ law



The names Π and Λ derive from the shape of the weight functions in our article on frequency counters E. Rubiola, On the measurement of frequency ... with high-resolution counters, RSI 76 054703, 2005

Experimental Method

Large input PM noise is used to emphasize the effect of aliasing

- Intentionally high PM noise at the input
- The scaled-down input noise is higher than the output-stage noise





Correlation reduces the background

Dividers Under Test

EPM3064A CPLD (Altera MAX 3000 Series, 64 macro-cells, speed grade 7 ns)



Π divider

Multi-buffer Π divider





A divider

The outputs are arguably independent Try to reduce the output-stage noise

White noise: The clock edges are independent **Correct for aliasing**

As Simple as That...



Results – Test on Aliasing



- Flicker region
 - Negligible aliasing
 - 1/D² law (-20 dB)

- White region
- Aliasing in the front-end -> +4 dB
- 1/D law and 1/D² law

Phase Noise of Real Dividers



- Flicker region –> Negligible aliasing
- The multibuffer Π divider is still not well explained
- The Λ divider exhibits low 1/f and low white noise

Allan Deviation in Real Dividers



• Slope $1/\tau$, typical of white and flicker PM noise

• The Λ divider performs 2×10^{-14} at $\tau = 1$ s, 10 MHz output



The **A Divider Versus the DDS**



- The Λ divider performs 2×10^{-14} at $\tau = 1$ s, 10 MHz output
- Thermal effects make the DDS worse at τ > 1 s
- The Λ divider is free from thermal effects – at the scale shown



The Bottom Line

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- Aliasing in traditional dividers
 - Increases white noise
 - Has little effect on flicker
- Flicker in multi-buffer Π divider not understood yet
- The new Λ divider
 - Is little/no affected by aliasing
 - Exhibits the lowest PM noise flicker: $b_{-1} \approx -130 \text{ dB}$ white: $b_0 \approx -165 \text{ dB}$
 - Features 2×10^{-14} at $\tau = 1$ s, 10 MHz output
 - Is free from the thermal effects seen in DDSs at $\tau > 1$ s

home page http://rubiola.org

Thanks – J. Groslambert, V. Giordano, M. Siccardi, J.-M. Friedt Grants from ANR (Oscillator IMP and First-TF network), and Region Franche Comte
Microwave Dividers

NB7L32M ÷2 µWave Divider 10 GHz ÷ 2 = 5 GHz Method



Compare two dividers

Use 5.01 GHz as a common oscillator, and beat

- Digital PM noise measurement at 10 MHz
- O-I: Two equal dividers
- O-O: Two outputs of the same divider
- Shown: spectrum of one divider

NB7L32M ÷2 µWave Divider

Phase noise vs input frequency



NB7L32M ÷2 µWave Divider

Works fairy well even at low input power (useful)



Notes

 At –16 dBm the white noise increases by 3 dB

- The critical power where (b₀)_φ = (b₀)_x is –16 dBm
- Hence

 (b₀)_{x-type} ≈ -140 dB

NBSG53A SiGe ÷2 µWave Divider



Method

- Use 5.01 (2.51) GHz as a pivot oscillator, and mixers
- Digital PM noise measurement at 10 MHz
- One divider shown

1/f -> pure gearbox model (as expected)

White -> aliased gearbox model (as expected)
 Debugged:
 -97.5 and -137* Likely, 1 dB discrepancy in w and 1/f (mixer response)

NBSG53A SiGe ÷2 µWave Divider



More noise and less tolerance to low power

NBSG53A SiGe ÷2 µWave Divider

Output vs Output gives info about the output stage



The problem seems in the gear box, rather in the output stage

Hittite HMC-C040, ÷10 Divider



Microwave Dividers Compared¹⁵³

	10 GHz ÷2	5 GHz ÷2	2.5 GHz ÷2	lower	
NB7L32M	-100	-109	-109	-109	600 MHz 1.2 GHz ÷2
NBSG53A	97.5	-103.5		-104	800 MHz 1.6 GHz ÷2
HMC-C040				-113	1 GHz 10 GHz ÷10
HMC705LP4		1 1		-121	0.5 GHz 2.5 GHz ÷5

Suggested Readings

Suggested Reading

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Bernard Widrow, Istvan Kollar *Quantization Noise* Cambridge 2008 ISBN 978-0-511-40990-5

 Chapter 15: Roundoff noise in FIR digital filters and in FFT calculations

 Appendix G: Quantization of a sinusoidal input

Quantization Noise

Roundoff Error in Digital Computation, Signal Processing, Control, and Communications

> Bernard Widrow István Kollár

ANALOG-DIGITAL CONVERSION

Walt Kester

Editor



Suggested Reading

Walt Kester (editor)

Analog-Digital Conversion

Analog Devices 2004 ISBN 0-916550-27-3

Marcel J.M. Pelgrom

Analog-to-Digital Conversion





Suggested Reading

Marcel J. M. Pelgrom Analog-to-Digital Conversion Springer 2010 ISBN 978-90-481-8888-8